

ЗАВИСИМОСТЬ СПЕКТРОВ И ЭФФЕКТИВНОСТИ СВЕТОДИОДОВ БЕЛОГО СВЕЧЕНИЯ НА ОСНОВЕ ГЕТЕРОСТРУКТУР ТИПА InGaN/AIGaN/GaN, ПОКРЫТЫХ РАЗЛИЧНЫМИ ЛЮМИНОФОРАМИ, ОТ ТЕМПЕРАТУРЫ

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Исследования зависимости спектров электролюминесценции и эффективности светодиодов белого свечения от температуры нагрева Т необходимы для понимания относительной роли свойств светодиодов синего свечения, возбуждающих люминофоры, и свойств разных люминофоров [1, 2], а также их взаимодействия. Зависимость свойств светодиодов от температуры Т также связана с нагревом светодиодов при больших токах. Это связано с важнейшей проблемой падения квантового выхода излучения с увеличением тока.

Исследовались светодиоды белого свечения ИРС-50 с кристаллами МК-24 на кремниевых подкристалльных платах. Корпус светодиодов изготовлен из дюоралюминия Д-16, линза – из оптического поликарбоната. Полость линзы заполнена силиконовым гелем SilGel 612. В качестве компаунда люминофорной смеси использован силикон LS-6257. Была выбрана серия светодиодов на основе кристаллов синего свечения [3] со следующими слоями гетероструктуры: n-GaN – 4 мкм; 10 периодов буферной сверхрешетки InGaN/GaN – 0,1 мкм; 8 периодов активной области – ~0,5 мкм (барьер/яма – ½); 2 периода нелегированной сверхрешетки u-AlGaN/u-GaN; слой p-GaN – ~0,1 мкм.

Образцы различались двумя люминофорами с одинаковой длиной волны возбуждения (\approx 460 нм): фирмы Intematix, Y4750 [$(\text{SrBaMg}_2)_2\text{SiO}_4:\text{Eu}^{2+}$] и НИИ «Платан», ФЛЖ-21 [$(\text{Gd}_x\text{Y}_{1-x})_3\text{Al}_5\text{O}_{12}:\text{Ce}^{3+}$].

Регистрация спектров проводилась при комнатной температуре в диапазоне токов 1 – 350 мА. Спектральное разрешение не хуже 0,1 нм.

Показано, что различие спектров светодиодов белого свечения с разными люминофорами (Y4750 и ФЛЖ-21) обусловлено как свойствами самих люминофоров (спектр ФЛЖ-21 неоднородно уширен в длинноволновую сторону), так и разным поглощением излучения синей линии кристаллов этими люминофорами: люминофор ФЛЖ-21 сильнее поглощает синее излучение, что приводит к увеличению показателя коротковолнового спада синей линии.

Интегральная интенсивность излучения светодиодов белого свечения уменьшается с увеличением температуры в интервале от 0 до +60 °C приблизительно с коэффициентом 0,55 – 0,33 %/°C. Большая часть падения интенсивности обусловлена падением интенсивности излучения люминофора. Пик интенсивности светодиода, соответствующий излучению люминофора, смещается на 1 – 2 нм.

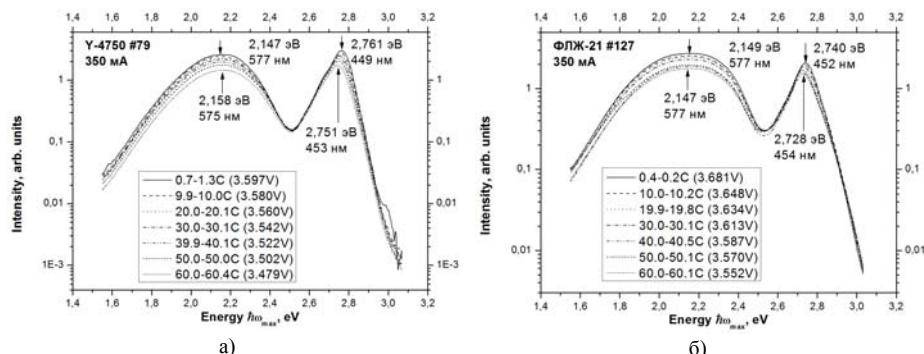


Рис. 1. Спектры электролюминесценции светодиодов с люминофором: а) Intematix Y4750 $(\text{SrBaMg}_2)_2\text{SiO}_4:\text{Eu}^{2+}$; б) НИИ «Платан» ФЛЖ-21 $(\text{Gd}_x\text{Y}_{1-x})_3\text{Al}_5\text{O}_{12}:\text{Ce}^{3+}$ при изменении температуры.

Форма синей линии в кристалле существенно меняется, как с длинноволновой (со стороны люминофора), так и с коротковолновой стороны. Знаменатель в показателе экспоненциального спада коротковолновой части пропорционален температуре $E_1 = m \cdot kT$, но величина коэффициента m существенно больше единицы, $m = 2,2 \div 9,0$. Это можно объяснить влиянием поглощения излучения кристалла люминофором.

При малых токах < 4 мА преобладает падение напряжения на параллельном сопротивлении светодиода R_{II} и вольтамперные характеристики на этом участке линейны. Значение параллельного сопротивления увеличивается с ростом T и не зависит от типа люминофора. С увеличением T КПД и световая отдача в области максимума зависимости КПД от тока уменьшается на 2,5% для светодиодов с люминофором Y4750 и на 8% для светодиодов с люминофором ФЛЖ-21.

Показано, что с увеличением T координаты цветности светодиодов белого свечения сдвигаются в область холодного свечения (0,374; 0,39) – (0,357; 0,345) вследствие уменьшения относительной доли излучения люминофора. Соответственно сдвигается коррелированная цветовая температура 4070 – 4506.

Светодиоды с люминофором Y4750 лучше для цветового восприятия человеческим глазом, в то время как светодиоды с люминофором ФЛЖ-21 имеют большие индексы цветопередачи и цветовую температуру. Повышение T приводит к сдвигу коррелированной цветовой температуры вследствие падения относительной роли люминофора.

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DEPENDENCE OF SPECTRA AND EFFICIENCY OF WHITE LIGHT-EMITTING DIODES BASED ON InGaN/AIGaN/GaN HETEROSTRUCTURES COVERED BY VARIOUS PHOSPHORS ON TEMPERATURE

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Researching dependence of electroluminescence spectra and efficiency of white light-emitting diodes on heating temperature are necessary for understanding a relative role of blue light-emitting diodes properties exciting phosphors and properties of different phosphors and also their interactions. White light-emitting diodes based on identical blue-emitting crystals covered by two various phosphors $[(SrBaMg_2)_2SiO_4:Eu^{2+}, (Gd_xY_{1-x})_3Al_5O_{12}:Ce^{3+}]$ with identical excitation wavelength (≈ 460 nm) were investigated. Spectra distinction of white light-emitting diodes with different phosphors is caused both phosphors properties (spectra FLJ-21 is inhomogeneously broadened to the long-wave side) and different absorption of blue-emitting crystals by these phosphors: phosphor FLJ-21 absorbs blue-emitting more strongly that leads to increasing short-wave decay index of blue line. Radiation intensity of white light-emitting diodes decreases with increasing temperature from 0 to +60 °C with factor 0,55 – 0,33 %/ °C. Temperature increasing leads to efficiency droop and also to shift of tristimulus values to cold luminescence region.

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